

# Silicon Bipolar Monolithic Dual Conversion Vector Modulator with Phase Shifter

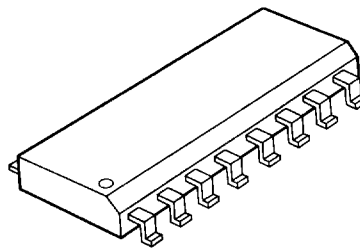
## Technical Data

HPMX-2004

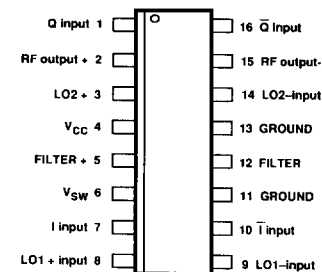
### Features

- On Board Active Digital Phase Shifter
- I/Q Bandwidth > 10 MHz
- Wide Bandwidth:  
1st LO, 40-240 MHz  
2nd LO, 250-2250 MHz  
RF Output, 250-2000 MHz
- On Chip Mixer for Dual Conversion
- Low Power Dissipation:  
Standby, 120  $\mu$ W  
Operating, 150 mW
- Low Cost Plastic Surface Mount Package

### Plastic S0-16 Package



### HPMX-2004 Pinout



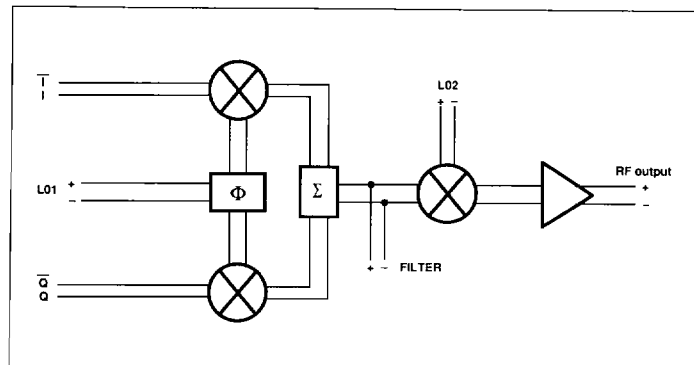
### Applications

- Digital Cellular and Cordless Telephones such as NADC, JDC, GSM, PCN, and PHP
- Wireless LANs
- RF Data Links
- Vector Generators

### Description

The HPMX-2004 is a silicon monolithic, dual conversion, quadrature modulator in a plastic, surface mount SO-16 package.

### Functional Block Diagram



*At the time this catalog was printed, this product was not yet released for sale. Please contact the local HP Field Sales Office for more information. All specifications are subject to change.*

The dual conversion architecture and wide band nature of the Gilbert cells allows operation over a broad range of frequencies with little change in performance. A low gain output stage is used to achieve a wide bandwidth with 50  $\Omega$  match.

All signal inputs and outputs except  $V_{SW}$  are differentially balanced with RF ports matched to 50  $\Omega$ , and can be used balanced or unbalanced in any

combination. Double balanced mixers are used to improve port to port isolation and reduce harmonic content in the output signal.

I and Q inputs are internally biased and have high input impedances to allow them to be driven from high impedance sources, either AC or DC coupled.

All on-chip circuitry is biased by a set of current sources con-

trolled by the standby circuit. When activated, the standby circuit turns all the current sources off, reducing current drain to only 25  $\mu$ A, the current required by the standby circuit alone.

This device is manufactured using Hewlett-Packard's 13 GHz  $f_T$ , 25 GHz  $f_{MAX}$  silicon bipolar integrated circuit process.

#### HPMX-2004 Absolute Maximum Ratings, $T_A = 25^\circ\text{C}^*$

Symbol	Parameter	Units	HPMX-2004
$V_{CC}$	Device Voltage, $T_{case} = 25^\circ\text{C}$	Volts	6
$V_{in}$ I/Q	I/Q Input Voltage	$V_{p-p}$	4
$P_{in}$ LO	Local Oscillator Input Power	dBm	+10
$V_{sw}$	Standby Mode Switch Voltage	Volts	6
$T_{op}$	Ambient Operating Temperature	$^\circ\text{C}$	-55 to +85
$T_{stg}$	Storage Temperature	$^\circ\text{C}$	-55 to +150

\*Operation in excess of any one of these conditions may result in permanent damage to this device. Care should be taken to prevent electrostatic discharge (ESD) that could permanently damage the device. This device has a Class 1 ESD rating.

Thermal Resistance: HPMX-2004 Thermal Resistance, Junction to Ambient,  $\Theta_{ja} = 160^\circ\text{C}/\text{W}$

#### Notes:

1. Junction temperature can be determined by  $T_j = (P_d \times \Theta_{ja}) + T_a$ .
2. Maximum soldering temperature is 260 $^\circ\text{C}$  for 5 seconds.

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**Electrical Parameters,  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5\text{ V}$**

Symbol	Parameters/Test Conditions: LO1 = -7 dBm @ 100 MHz, LO2 = -3 dBm @ 900 MHz, I/Q = $1.2 V_{p-p}$ @ 70 kHz, $Z_o = 50\ \Omega$ , Test Circuit #1 (unless otherwise noted)	Units	Typical
$I_{cc}$	Power Supply Current	mA	30
$I_{cc}$	Standby Current, $V_{sw} = +3.0\text{ V}$	mA	21
	I/Q Input Impedance (Internally Biased with High Impedance Source to $\approx 2.5\text{ VDC}$ )	Ohms pF	8,000 1.0
	LO1 Operating Frequency Range	MHz	40 to 240
	LO2 Operating Frequency Range	MHz	250 to 2,000
	I/Q Modulating Frequency Range	MHz	DC to 10
	RF Output Frequency Range	MHz	250 to 2,000
$T_{on}$	Turn-On Time, to $\pm 0.5\text{ dB}$ of Final Output Power (Test Circuit #4)	$\mu\text{S}$	1.2
$T_{off}$	Turn-Off Time, to Output Power Below Noise Floor (Test Circuit #4)	$\mu\text{S}$	0.4

**800 MHz RF Electrical Parameters,  $T_A = 25^\circ\text{C}$ ,  $V_{CC} = 5\text{ V}$**

Symbol	Parameters/Test Conditions: LO1 = -7 dBm @ 100 MHz, LO2 = -3 dBm @ 900 MHz, I/Q = $1.2 V_{p-p}$ differential @ 70 kHz, $Z_o = 50\ \Omega$ , Test Circuit #2 (unless otherwise noted)	Units	Typical	
$P_{out}$	RF Output Power @ 800 MHz	dBm	-13.0	
	RF Output Power Flatness, 800-1000 MHz	dB	$\pm 0.6$	
$P_{1dB}$	Power Output at 1 dB Compression Point (I/Q voltage swept)	dBm	-12.5	
LO1 $P_{in}$	LO1 Power Input for Phase Shift of $90^\circ \pm 3^\circ$	dBm	-7	
Noise	Output Noise Floor	dBm/Hz	-136	
	Modulation Product Power	Residual LO (800 MHz)	dBc	-34
	Levels in dB Relative to the Desired Sideband	Undesired Sideband (799.93 MHz)	dBc	-41
	Using Filter at	2nd Harmonic ( $800 \pm 0.140\text{ MHz}$ )	dBc	-49
	1st Carrier Output	3rd Harmonic ( $800 \pm 0.210\text{ MHz}$ )	dBc	-53
		5th Harmonic ( $800 \pm 0.350\text{ MHz}$ )	dBc	-72
	LO1 Input SWR	VSWR	2.0:1	
	LO2 Input SWR	VSWR	1.2:1	
	RF Output SWR (operating)	VSWR	1.5:1	
$A_i$	I/Q Amp. Imbalance (derived from undesired sideband data)	dB	$\pm 0.15$	
$P_i$	I/Q Phase Imbalance (derived from undesired sideband data)	Deg.	$\pm 0.97$	

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